

PROCEEDINGS OF SPIE

Organic and Hybrid Field-Effect Transistors XVIII

Iain McCulloch
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Editors

12–15 August 2019
San Diego, California, United States

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Millipore Sigma (United States)
Journal of Materials Chemistry C (United Kingdom)

Published by
SPIE

Volume 11097

Proceedings of SPIE 0277-786X, V. 11097

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Author(s), "Title of Paper," in *Organic and Hybrid Field-Effect Transistors XVIII*, edited by Iain McCulloch, Oana D. Jurchescu, Proceedings of SPIE Vol. 11097 (SPIE, Bellingham, WA, 2019) Seven-digit Article CID Number.

ISSN: 0277-786X
ISSN: 1996-756X (electronic)

ISBN: 9781510628878
ISBN: 9781510628885 (electronic)

Published by

SPIE

P.O. Box 10, Bellingham, Washington 98227-0010 USA
Telephone +1 360 676 3290 (Pacific Time): Fax +1 360 647 1445

SPIE.org

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